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INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Complete if Known	
				Application Number	New Application
				Filing Date	March 23, 2006
				First Named Inventor	Dieter HUHSE et al
				Group Art Unit	
				Examiner Name	
				Confirmation No.	
Sheet	1	of	3	Attorney Docket Number	3286-103

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code ² (if known)		
/SAT/	1.	3,445,167		Armstrong et al	5/20/69
	2.	5,499,190	A	Takahashi et al	3/12/96
	3.	5,955,875	A	Twichell et al	9/21/99
	4.	6,388,753	B1	Hall et al	5/14/02
	5.	6,028,424	A	Twichell et al	2/22/00
	6.	5,614,834	A	Black et al	3/25/97
	7.	2002/0097761	A1	Sucha et al	7/25/02
/SAT/	8.	2004/0051926	A1	Gulden et al	3/18/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code. ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language translation is attached. AB indicates that only an English language abstract is attached.

/Samuel A. Turner/ 01/25/2008

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FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	T ⁶
		Office ³ Code	Number ⁴	Kind ⁵ (if known)			
/SAT/	9.	JP	05347346		NEC Corp.	12/27/93	AB
/SAT/	10.	JP	02064433		Nippon Telegr & Teleph Corp.	3/5/90	AB
/SAT/	11.	DE	100 47 170	A1	Siemens AG	4/25/02	
Examiner Signature	/Samuel A. Turner/				Date Considered	01/25/2008	

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NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²	
/SAT/	12.	Schimpe et al., "Characterisation of Frequency Response of 1.5 MUM INGAASP DFB Laser Diode and INGAAS...", ELECTRONICS LETTERS, vol. 22, no. 9, April 24, 1986, pgs. 453-454.		
/SAT/	13.	Reimann et al., "Advanced semiconductor laser based electro-optical sampling system using soliton pulse compression for direct probing at 1.55-/spl mu/m wavelength", LASERS AND ELECTRO-OPTICS SOCIETY ANNUAL MEETING, 1988, vol. 1, December 1, 1998, pgs. 215-216.		
/SAT/	14.	Reimann et al., "Low jitter dual semiconductor laser system using electrical phase shift for fast temporal scanning in time-resolved pump and probe experiments", LASERS AND ELECTRO-OPTICS, 1999, vol. 2, August 30, 1999, pgs. 203-204.		
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